

Notice of References Cited	Application/Control No. 10/040,122	Applicant(s)/Patent Under Reexamination SCOTT ET AL.	
	Examiner Leigh Marie Garbowski	Art Unit 2825	Page 1 of 3

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Applicant(s)/Patent Under
Reexamination
SCOTT ET AL.

Examiner

Leigh Marie Garbowski

Art Unit

2825

Page 2 of 3

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SCOTT ET AL.Examiner
Leigh Marie GarbowskiArt Unit
2825

Page 3 of 3

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